

# COURSE DETAIL

## VLSI SYSTEM TESTING

**Country**

Taiwan

**Host Institution**

National Taiwan University

**Program(s)**

National Taiwan University

**UCEAP Course Level**

Upper Division

**UCEAP Subject Area(s)**

Electrical Engineering

**UCEAP Course Number**

102

**UCEAP Course Suffix****UCEAP Official Title**

VLSI SYSTEM TESTING

**UCEAP Transcript Title**

VLSI SYSTEM TEST

**UCEAP Quarter Units**

4.50

**UCEAP Semester Units**

3.00

## Course Description

With the advancement in Integrated Circuit (IC) fabrication and integration technologies, design-for-test and system-level testing have become indispensable. This course discusses concepts and technologies in VLSI testing. It starts with fault modeling, fault simulation, and test pattern generation. Then, the course introduces design-for-test, built-in-self-test, and memory testing. Finally, the course will address challenges and solutions to system-level tests.

## Language(s) of Instruction

English

## Host Institution Course Number

EEE5011

## Host Institution Course Title

VLSI SYSTEM TESTING

## Host Institution Course Details

[https://nol.ntu.edu.tw/nol/coursesearch/print\\_table.php?course\\_id=943%20U0110&c...](https://nol.ntu.edu.tw/nol/coursesearch/print_table.php?course_id=943%20U0110&c...)

## Host Institution Campus

## Host Institution Faculty

College of Electrical Engineering and Computer Science

## Host Institution Degree

## Host Institution Department

Graduate Institute of Electrical Engineering

## Course Last Reviewed

2023-2024

[Print](#)